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APPLICANTS

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** CONTINUING DATA *10/750,470*

** FOREIGN APPLICATIONS *Ch*

REPUBLIC OF KOREA 2003-2599 01/15/2003

IF REQUIRED, FOREIGN FILING LICENSE GRANTED

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Foreign Priority claimed	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	STATE OR COUNTRY KOREA, REPUBLIC OF	SHEETS	TOTAL CLAIMS	INDEPENDENT CLAIMS
35 USC 119 (a-d) conditions met	<input checked="" type="checkbox"/> yes <input type="checkbox"/> no <input type="checkbox"/> Met after Allowance		DRAWING 4	26	4
Verified and Acknowledged	<i>Calvona</i> <i>ee</i> Examiner's Signature Initials				

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TITLE

Method for inspecting a wafer and apparatus for inspecting a wafer

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